

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT <small>(Use several sheets if necessary)</small>			ATTY DOCKET NO.: E30.2Q-8140- US16		APPLICATION NO.: 10/609242			
			APPLICANT: John C. Pederson					
			FILING DATE: June 27, 2003		GROUP: 2636			
REFERENCE DESIGNATION			U.S. PATENT AND PUBLISHED APPLICATION DOCUMENTS					
EXAMINER'S INIT.	DOCUMENT NUMBER	DATE	NAME		CLASS/ SUBCLASS	FILING DATE IF APPROPRIATE		
AA								
AB								
AC								
AD								
AE								
AF								
AG								
AH								
AI								
AJ								
AK								
AL								
FOREIGN PATENT DOCUMENTS								
	DOCUMENT NUMBER	DATE	COUNTRY					
BA	GB 2 139 340 A	11/07/1984	United Kingdom					
BB	06-333403	12/02/1994	Japan					
BC	08-002341	01/09/1996	Japan					
BD								
BE								
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER	CA							
	CB							
	CC							
EXAMINER		DATE CONSIDERED		4/10/05				
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1 of 1



UNPUBLISHED US APPLICATIONS NOT RELATED BY PRIORITY (COPIES ENCLOSED)	ATTY DOCKET NO.: E30.2Q-8140-US16		APPLICATION NO. 10/609242
	APPLICANT: John C. Pederson		
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UNPUBLISHED US APPLICATIONS NOT RELATED BY PRIORITY

EXAM'S INIT.		APPLICATION NO.	FILING DATE	INVENTOR(S)
	DA			
	DB			
	DC			
	DD			
	DE			

EXAMINER **DATE CONSIDERED**

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US APPLICATIONS RELATED BY PRIORITY (COPIES NOT ENCLOSED)	ATTY DOCKET NO.: E30.2Q-8140-US16		APPLICATION NO. 10/609242
	APPLICANT: John C. Pederson		
	FILING DATE: June 27, 2003		GROUP: 2636

US APPLICATIONS RELATED BY PRIORITY

EXAM'S INIT		APPLICATION NO.	FILING DATE	PATENT NO.	INVENTOR(S)	FORM 1449/892 ENC
JR	EA	09/590610	06/09/2000	6590502	John C. Pederson	Yes
	EB					
	EC					
	ED					
	EE					
	EF					

EXAMINER *John C. Pederson* **DATE CONSIDERED** *4/15/05*

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U. S. PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

ATTY DOCKET NO.: E30.2Q-8140-US16

APPLICATION NO.: 10/609242

APPLICANT: John C. Pederson

FILING DATE: June 27, 2003

GROUP: 2636

REFERENCE DESIGNATION

U. S. PATENT AND PUBLISHED APPLICATION DOCUMENTS

EXAM'S INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE IF APPROPRIATE
	AA					

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY
✓	BA	0531184A1	03/10/1993	EUROPE (includes English Abstract)
	BB	0531185A1	03/10/1993	EUROPE (includes English Abstract)
	BC	0596782A1	05/11/1994	EUROPE (includes English Abstract)
	BD	0633163A1	01/11/1995	EUROPE (includes English Abstract)
	BE	0688696A2	12/27/1995	EUROPE (includes English Abstract)
	BF	0793403B1	09/03/1997	EUROPE (includes English Abstract)
	BG	0896898A2	07/17/1998	EUROPE (includes English Abstract)
	BH	FR2658024	08/09/1991	FRANCE (includes English Abstract)
	BI	FR2680861	03/05/1993	FRANCE (includes English Abstract)
	BJ	FR2707222	01/13/1995	FRANCE (includes English Abstract)
	BK	FR2800500	05/04/2001	FRANCE (includes English Abstract)
	BL	DE4304216	08/18/1994	GERMANY (includes English Abstract)
	BM	DE29712281	01/22/1998	GERMANY (includes English Abstract)
	BN	JP60143150	07/29/1985	JAPAN (includes English Abstract)
	BO	JP6333403	12/02/1994	JAPAN (includes English Abstract)
✓	BP	JP8002341	01/09/1996	JAPAN (includes English Abstract)

OTHER ART (Including Author, Title, Date, Pertinent Pages, Ect.)

	CA		
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REFERENCE DESIGNATION		U.S. PATENT AND PUBLISHED APPLICATION DOCUMENTS			
EXAM'S INIT.	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE IF APPROPRIATE
BU	AB 3469686	09/30/1969	H.W. Gutsche et al.	—	
1	ACC 3705316	12/05/1972	Burrous et al.	307/311	
	AE 3867718	02/18/1975	Moe		
	AG 4254453	03/03/1981	Mouyard et al.		
	AH 4271408	06/02/1981	Teshima et al.		
	AL 4336580	06/22/1982	Mouyard et al.		
	AO 4434510	02/28/1984	Lemelson	455/603	
	AP 4445132	04/24/1984	Ichikawa et al.	357/32	
	APP 4556862	12/03/1985	Meinershagen	340/67	
	AR 4614866	09/30/1986	Liss et al.	250/214	
	AD 4710977	12/01/1987	Lemelson	455/603	
	AG 4724312	02/09/1988	Snaper	250/203	
	AH 4742432	05/03/1988	Thillays et al.		
	AJ 4821338	04/11/1989	Naruse et al.	455/617	
	AK 4868719	09/19/1989	Kouchi et al.		
	AM 4928084	05/22/1990	Reiser		
	AS 4975814	12/04/1990	Schairer		
	AU 5000569	03/19/1991	Nylund	356/237	
	AA 5038406	08/06/1991	Titterton et al.	359/113	
	AB 5041947	08/20/1991	Yuen et al.	—	
	AE 5060303	10/22/1991	Wilmoth	359/152	
	AF 5067788	11/26/1991	Jansson et al.	385/2	
	AFF 5091828	2/25/92	Jincks et al.	—	
	AM 5159486	10/27/1992	Webb	359/229	
	ANN 5198756	03/30/1993	Gyugyi et al	323/207	
	AP 5224773	07/06/1993	Arimura	362/227	
BU	AT 5291196	03/01/1994	Defour	340/961	
EXAMINER <i>J. L. S. G.</i>		DATE CONSIDERED <i>6/15/05</i>			
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REFERENCE DESIGNATION		U.S. PATENT AND PUBLISHED APPLICATION DOCUMENTS			CLASS/ SUBCLASS	FILING DATE IF APPROPRIATE
EXAM'S INIT.	DOCUMENT NUMBER	DATE	NAME			
✓ AU	5298738	03/29/1994	Gebert et al.	250/222		
✓ AV	5302965	04/12/1994	Belcher et al.	345/31		
✓ AF	5361190	11/10/1994	Roberts et al.	362/61		
✓ AH	5400140	03/21/1995	Johnston	356/345		
✓ AK	5410328	04/25/1995	Yoksza et al.	345/82		
✓ AL	5410453	04/25/1995	Ruskouski	—		
✓ AM	5416627	05/16/1995	Wilmoth	359/159		
✓ AP	5422623	06/06/1995	Bader et al.	340/331		
✓ AQ	5426417	06/20/1995	Stanuch	—		
✓ AR	5434693	07/18/1995	Tanaka et al.	359/180		
✓ AS	5436809	07/25/1995	Brassier et al.	—		
✓ AU	5465142	11/07/1995	Krumes et al.	356/5.01		
✓ AV	5471371	11/28/1995	Koppolu et al.	—		
✓ AC	5490049	02/06/1996	Montalan et al.	362/240		
✓ AJ	5532472	07/02/1996	Furuta	250/214		
✓ AN	5580156	12/03/1996	Suzuki et al.	362/184		
✓ APP	5593459	01/14/97	Gamblin	8/539		
✓ AQ	5594415	01/14/1997	Iskikawa et al.	—		
✓ AR	5604480	02/18/1997	Lamparter	✓		
✓ AS	5606444	02/25/1997	Johnson et al.	359/152		
✓ AT	5612201	03/18/1997	De Plaen et al.	—		
✓ ABB	5634287	06/03/1997	Lamparter	—		
✓ ACC	5643357	06/03/1997	Nutter et al.	—		
✓ ADD	5635902	06/03/1997	Hochstein	—		
✓ AE	5636916	06/10/1997	Sokolowski	—		
✓ AG	5660461	08/26/1997	Ignatius et al.	—		
✓ AII	5664448	09/09/1997	Swan et al.	—		
EXAMINER	<i>J. L. L. M.</i>		DATE CONSIDERED	4/15/05		
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EXAM'S INIT.	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE IF APPROPRIATE	
TC	AO 5726535	03/10/1998	Yan	315/185		
	AP 5726786	03/10/1998	Heflinger	359/152		
	AQ 5734343	03/31/1998	Urbish et al.	340/942		
	AR 5736925	04/07/1998	Knauff et al.	340/468		
	AA 5785418	07/28/1998	Hochstein	362/373		
	AB 5786918	07/28/1998	Suzuki et al.	359/135		
	AI 5808592	09/15/1998	Mizutani et al.	345/83		
	AJ 5826965	10/27/1998	Lyons	362/74		
	AK 5828055	0/27/1998	Jebens	250/214		
	AN 5838259	11/17/1998	Tonkin			
	AP 5872646	02/16/1999	Alserman et al.	359/169		
	AR 5900850	05/04/1999	Bailery et al.	345/55		
	AS 5917637	06/29/1999	Iskikawa et al.	359/181		
	AV 5931570	08/03/1999	Yamuro	362/355		
	AA 5932860	08/03/1999	Plesko	235/454		
	AC 5939996	08/17/1999	Kniveton et al.	340/815.4		
	AD 5959752	09/28/1999	Ota	359/152		
	AE 5960135	09/28/1999	Ozawa	385/24		
	AF 5965879	12/10/1999	Leviton	250/231.13		
	AG 5966073	10/12/1999	Walton			
	AI 5990802	11/23/1999	Maskeny	340/815.45		
	AK 6014237	01/11/2000	Abeles et al.	359/124		
	AN 6067010	05/23/2000	Wang			
	AO 6067011	05/23/2000	Leslie			
	AP 6067018	05/23/2000	Skelton et al.	340/573.3		
	APP 6086229	07/1/2000	Pastrick	362/494		
	AQ 6091025	07/18/2000	Cotter et al.	174/110		
↓	AT 6106137	08/22/2000	Adams et al.			
EXAMINER	<i>M. Schaefer</i>		DATE CONSIDERED	<i>4/15/05</i>		

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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

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